

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. 30-5004(4015)	SERIAL NO. 09/465,492	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Vladimir Segal et al.		
					FILING DATE December 16, 1999	GROUP 1742	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	5,171,379	12-1992	Kumar et al.			
HW	AB	5,194,101	03-1993	Worcester et al.			
HW	AC	6,521,173 B2	02-2003	Kumar et al.			
HW	AD	4,844,746	07-1989	Hormann et al.			
	AE						
HW	AF	US2002/0041819 A1	04-2002	Kumar et al.			Jul. 16, 2001
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
HW	AM	62-297463	12-1987	Japan			
HW	AN	EP 0 902 102 A1	03-1999	EPO			
HW	AO	03-197640	08-1991	Japan			
HW	AP	EP 0 281 141 B2	06-2000	EPO			
HW	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AR		Susumu Sawada, "On Advanced Sputtering Targets of Refractory Metals and Their Silicides for VLSI-Applications", 12 th International Plansee Seminar (1989) Topic 5: Ultrapure Refractory Metals, pp. 201-222.				
HW	AS		P. Ding et al., "Copper Barrier, Seed Layer, and Planarization Technologies", June 10-12, 1997 VMIC Conference, pp. 87-92.				
HW	AT		"Nickel, Cobalt and Their Alloys", pub. By ASM International, December 2000, pages 76, 230-234.				
EXAMINER	<i>Harry S. W. M. J. H.</i>			DATE CONSIDERED 2/12/04			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
30-5004(4015)SERIAL NO.
09/465,492LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Vladimir Segal et al.FILING DATE
December 16, 1999GROUP
1742DEC 17 2003
U.S. PATENT OFFICE

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*Examiner Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
NW	AA	6,454,994	09-2002 Wang			
NW	AB	6,139,701	10-2000 Pavate et al.			
	AC					
	AD					
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	AG					JAN 03 2004
	AH					TC 1700
	AI					
	AJ					
	AK					
	AL					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
NW	AM	JP59227992A	12-1984 JP				
	AN						
	AO						
	AP						
	AQ						

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NW	AR	Friedman. "Grain Size Refinement in a Tantalum Ingot", Metallurgical Transactions. Vol. 2 No. 1, January 1971, pages 337-341.
	AS	
	AT	

EXAMINER
2/12/04

DATE CONSIDERED

Dany S. Willith

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					APPLICANT Vladimir Seidl et al.		
					FLYING DATE December 16, 1994	GROUP 1742	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
HW	AA	3,197,102 3,197,102	02-1970 -82-1970	Douglas et al (Douglas et al.)			
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	AC						
	AD						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
HW	AM	JP H03-197610A JP-H03-197610A	08-1991 08-1991	JP (Translation of claims only)			Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Permanent Page, etc.)							
	AR						
	AS						
	AT						
EXAMINER 2/12/04		DATE CONSIDERED	<i>Harry S. Will, Jr.</i>				
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